



Shenzhen Tuofeng Semiconductor Technology Co., Ltd

**N-CHANNEL ENHANCEMENT MODE POWER MOSFET**

SGT MOS、低内阻、低结电容开关损耗小

**TF060N04NG****• General Description**

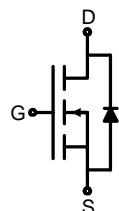
The TF060N04NG combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ . This device is ideal for load switch and battery protection applications.

**• Features**

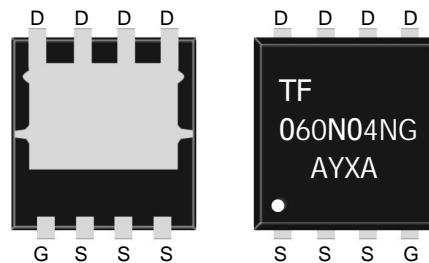
- Advance high cell density Trench technology
- Low  $R_{DS(ON)}$  to minimize conductive loss
- Low Gate Charge for fast switching
- Low Thermal resistance

**• Application**

- MB/VGA Vcore
- SMPS 2<sup>nd</sup> Synchronous Rectifier
- POL application
- BLDC Motor driver

**• Product Summary**

$V_{DS} = 40V$     $I_D = 50A$   
 $R_{DS(ON)(10V\ typ)} = 6.0m\Omega$   
 $R_{DS(ON)(4.5V\ typ)} = 8.2m\Omega$

**PDFNWB5x6-8L****• Ordering Information:**

Part NO.	TF060N04NG
Marking 1	060N04NG
Marking 2	TF:tuofeng; AA:device code; Y:year code; X:Week
MOQ	5000

**• Absolute Maximum Ratings ( $T_C = 25^\circ C$ )**

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D @ T_C = 25^\circ C$	50	A
	$I_D @ T_C = 75^\circ C$	42	A
	$I_D @ T_C = 100^\circ C$	30	A
Pulsed Drain Current <sup>①</sup>	$I_{DM}$	180	A
Total Power Dissipation	$P_D @ T_C = 25^\circ C$	45	W
Total Power Dissipation	$P_D @ T_A = 25^\circ C$	2.0	W
Operating Junction Temperature	$T_J$	-55 to 150	°C
Storage Temperature	$T_{STG}$	-55 to 150	°C

Note: ① Pulse Test : Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$  ;



Shenzhen Tuofeng Semiconductor Technology Co., Ltd

**N - CHANNEL ENHANCEMENT MODE POWER MOSFET**

SGT MOS、低内阻、低结电容开关损耗小

**TF060N04NG**

Single Pulse Avalanche Energy	$E_{AS}$	39	mJ
Avalanche Current	$I_{AS} I_{AR}$	15	A

**•Thermal resistance**

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	$R_{thJC}$	-	-	4.5	° C/W
Thermal resistance, junction - ambient	$R_{thJA}$	-	-	60	° C/W
Soldering temperature, wave soldering for 8s	$T_{sold}$	-	-	265	° C

**•Electronic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	40			V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 250\mu A$	1.0	1.7	2.5	V
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS}=40V, V_{GS} = 0V$			1.0	$\mu A$
Gate- Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS} = 0V$			$\pm 100$	nA
Static Drain-source On Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=20A$		6.0	8.0	$m\Omega$
		$V_{GS}=4.5V, I_D=15A$		8.2	12	$m\Omega$
Forward Transconductance	$g_{FS}$	$V_{DS} = 25V, I_D=10A$		15		S
Source-drain voltage	$V_{SD}$	$I_S=20A$			1.20	V

**•Electronic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	$C_{iss}$	$V_{DS}=20V, V_{GS}=0V$ $f = 1MHz$	-	795	-	pF
Output capacitance	$C_{oss}$		-	168	-	
Reverse transfer capacitance	$C_{rss}$		-	12.9	-	

**•Gate Charge characteristics( $T_a = 25^\circ C$ )**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Gate Resistance	$R_g$	$f = 1MHz$		1.3		$\Omega$
Total gate charge	$Q_g$	$V_{DD} = 20V$ $I_D = 20A$ $V_{GS} = 10V$	-	14.4	-	nC
Gate - Source charge	$Q_{gs}$		-	2.4	-	
Gate - Drain charge	$Q_{gd}$		-	2.3	-	
Turn-ON Delay time	$t_{D(on)}$	$V_{GS}=10V, V_{DS}=20V$ $R_G = 3.0\Omega, I=20A$		5.70		ns
Turn-ON Rise time	$t_r$			4.10		ns
Turn-Off Delay time	$t_{D(off)}$			14.7		ns
Turn-Off Fall time	$t_f$			4.00		ns

### Typical Characteristics

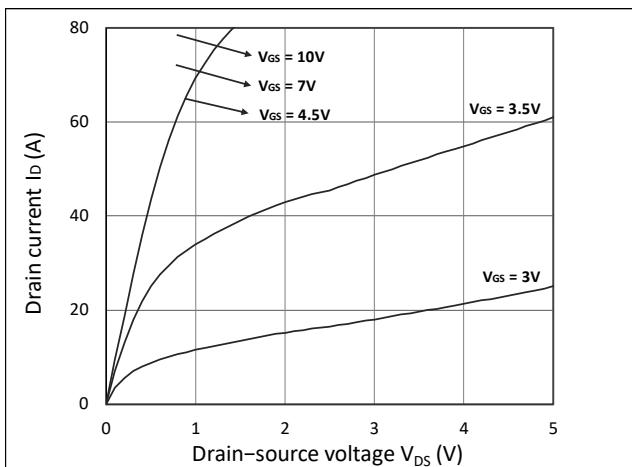


Figure 1. Output Characteristics

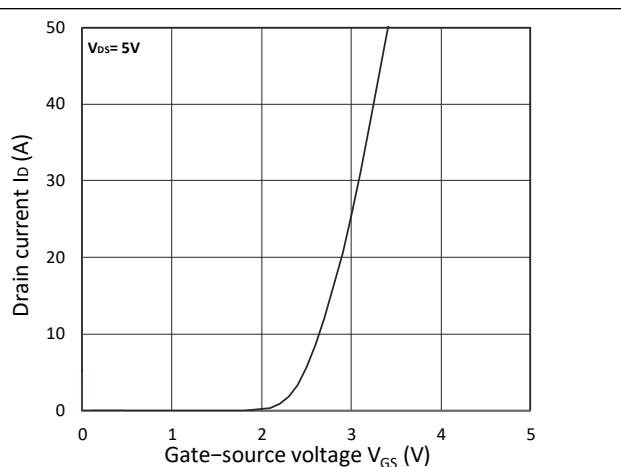


Figure 2. Transfer Characteristics

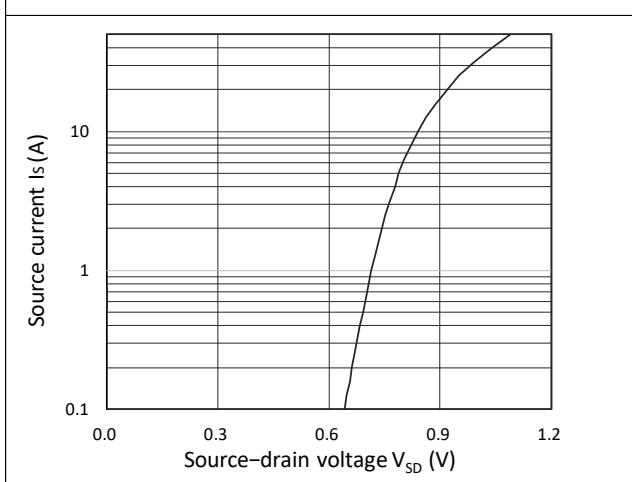


Figure 3. Forward Characteristics of Reverse

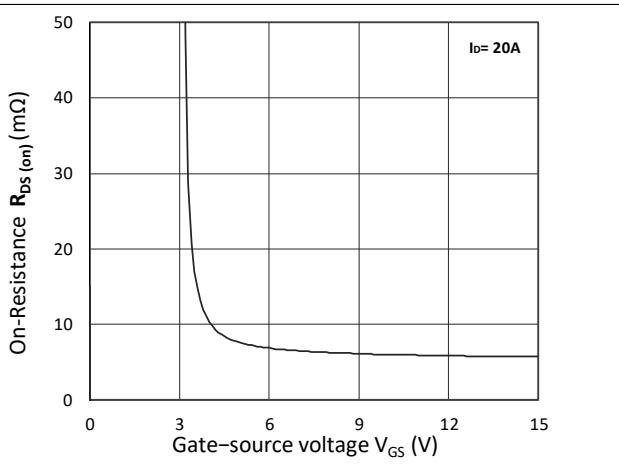


Figure 4.  $R_{DS(on)}$  vs.  $V_{GS}$

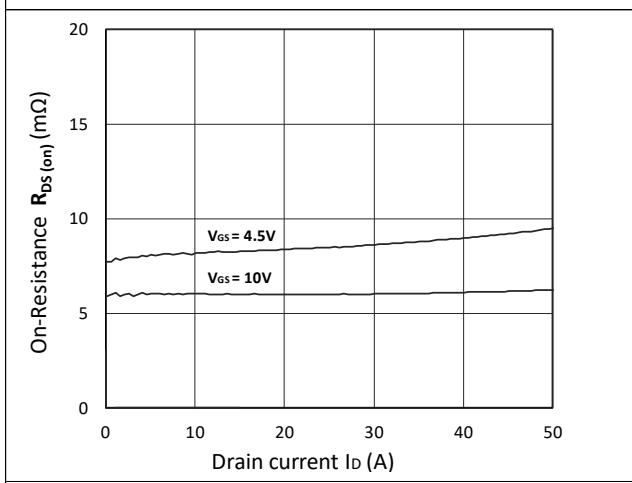


Figure 5.  $R_{DS(on)}$  vs.  $I_D$

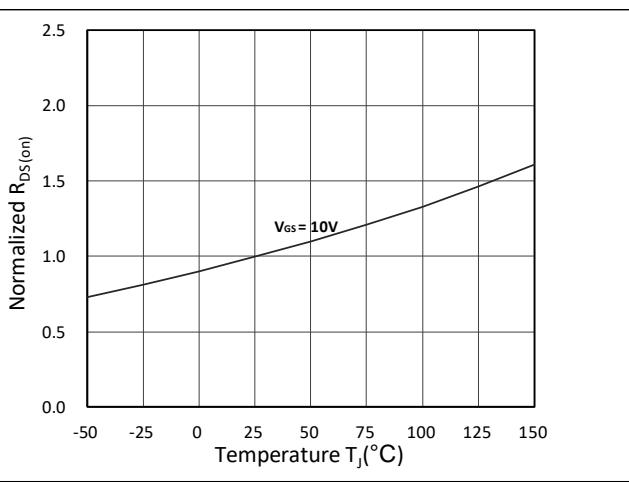


Figure 6. Normalized  $R_{DS(on)}$  vs. Temperature

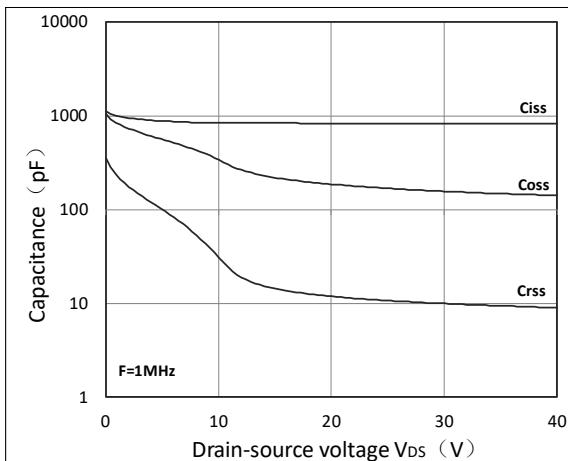


Figure 7. Capacitance Characteristics

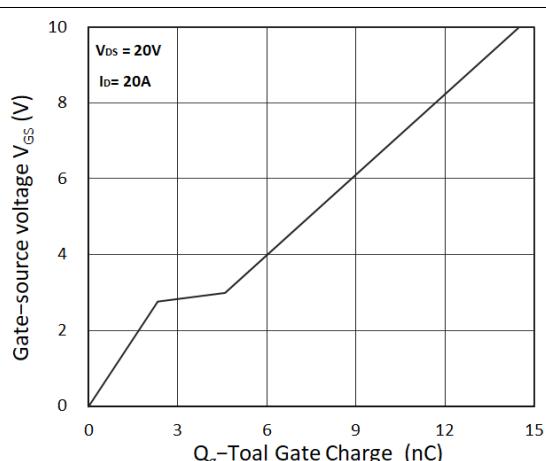


Figure 8. Gate Charge Characteristics

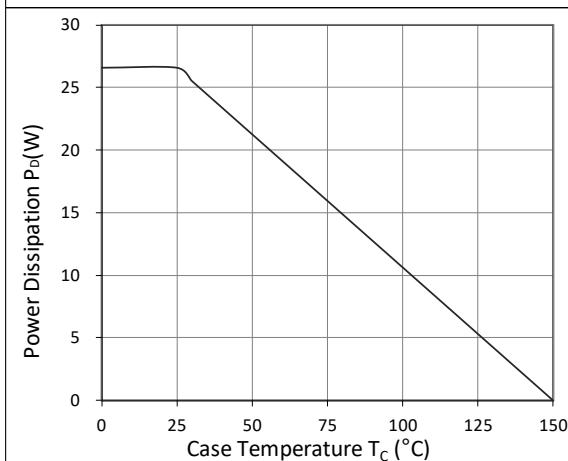


Figure 9. Power Dissipation

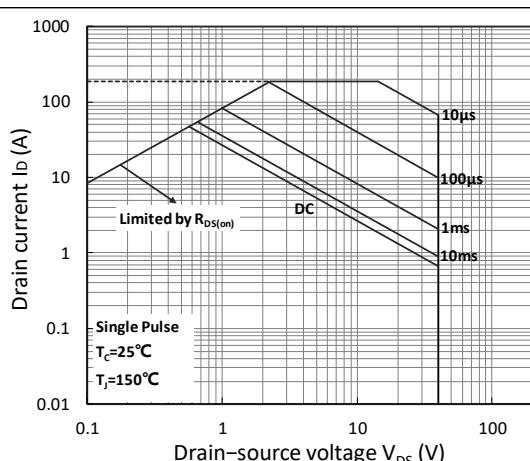


Figure 10. Safe Operating Area

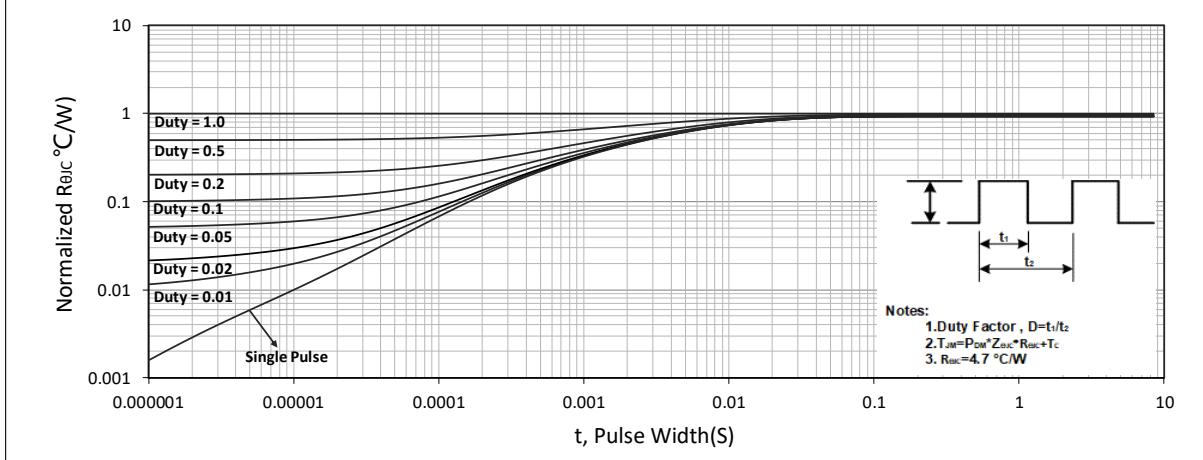


Figure 11. Normalized Maximum Transient Thermal Impedance

### Test Circuit

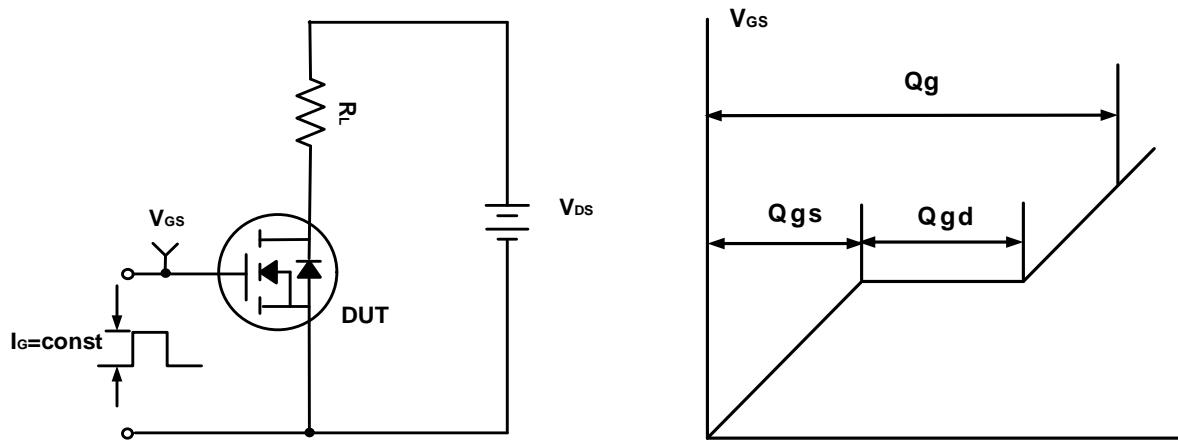


Figure A. Gate Charge Test Circuit & Waveforms

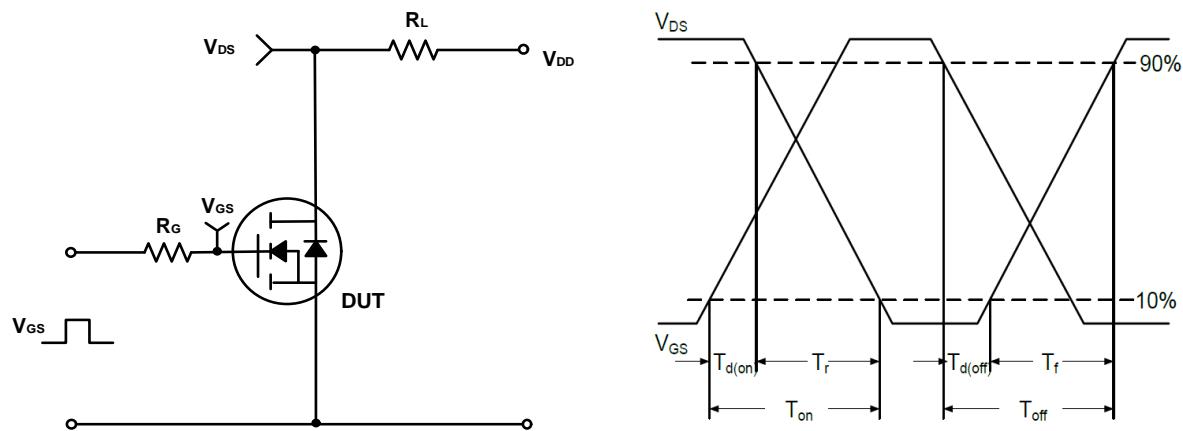


Figure B. Switching Test Circuit & Waveforms

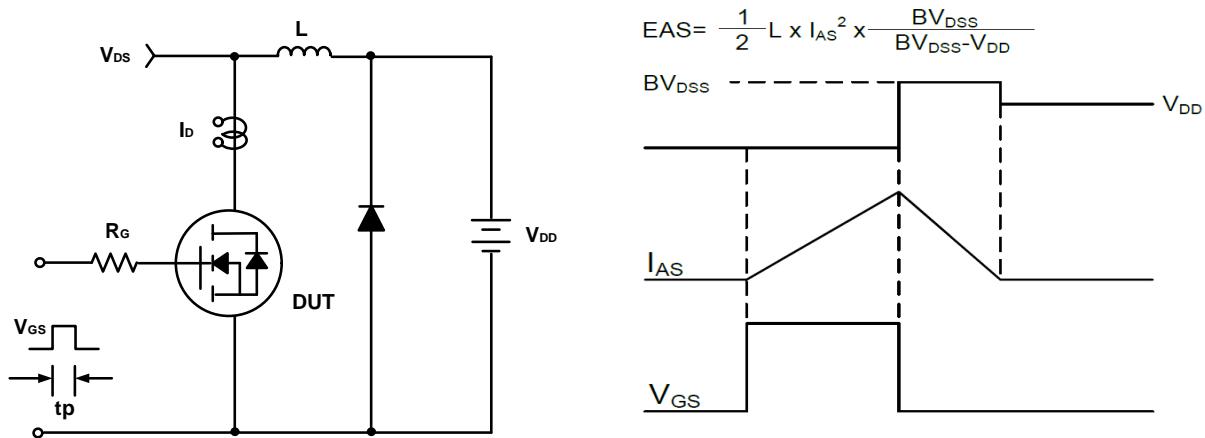


Figure C. Unclamped Inductive Switching Circuit & Waveforms



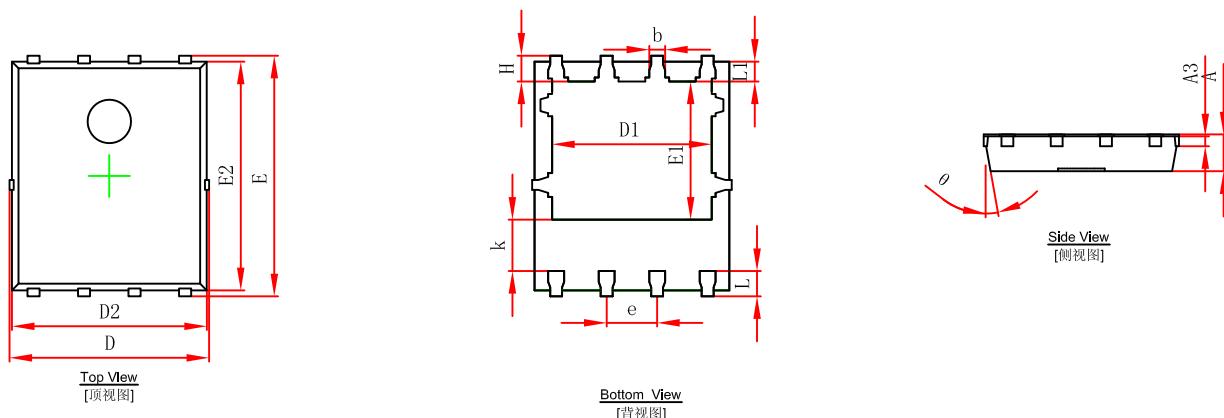
Shenzhen Tuofeng Semiconductor Technology Co., Ltd

## N-CHANNEL ENHANCEMENT MODE POWER MOSFET

SGT MOS、低内阻、低结电容开关损耗小

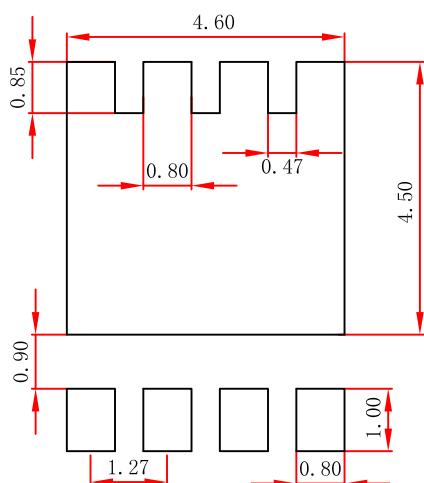
**TF060N04NG**

### PDFNWB5x6-8L Package Outline Dimensions



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°

### PDFNWB5x6-8L Suggested Pad Layout



- Note:  
1. Controlling dimension:in millimeters.  
2. General tolerance: $\pm 0.05\text{mm}$ .  
3. The pad layout is for reference purposes only.